

FDS4435A

P-Channel Logic Level PowerTrench® MOSFET

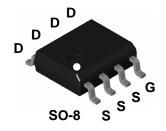
General Description

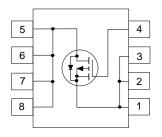
This P-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance.

These devices are well suited for notebook computer applications: load switching and power management, battery charging circuits, and DC/DC conversion.

Features

- -9 A, -30 V. $R_{DS(ON)}$ = 0.017 Ω @ V_{GS} = -10 V $R_{DS(ON)}$ = 0.025 Ω @ V_{GS} = -4.5 V
- Low gate charge (21nC typical).
- \bullet High performance trench technology for extremely low $R_{_{\mathrm{DS(ON)}}}.$
- High power and current handling capability.





Absolute Maximum Ratings T_a = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-30	V
V _{GSS}	Gate-Source Voltage		± 20	V
I _D	Drain Current - Continuous	(Note 1a)	-9	А
	- Pulsed		-50	
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
T _J , T _{stg}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

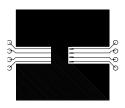
$R_{_{\theta}JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
R _e JC	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

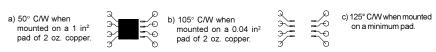
Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity	
FDS4435A	FDS4435A	13"	12mm	2500 units	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	1	•	•		•
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-30			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A,Referenced to 25°C		-26		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, V_{GS} = 0$ $T_{J} = 125^{\circ}\text{C}$			-1 -10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Chara	acteristics (Note 2)					•
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-1	-1.7	-2	V
$\Delta V_{GS(th)} = \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = -250 μ A,Referenced to 25°C		4.2		mV/°C
	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -9 A		0.015	0.017	Ω
		T _J = 125°C		0.021	0.030	1
		V _{GS} = -4.5 V, I _D = -7 A		0.023	0.025	
I _{D(on)}	On-State Drain Current	V _{GS} = -10 V, V _{DS} = -5 V	-40			Α
g FS	Forward Transconductance	V _{DS} = -10 V, I _D = -9 A		25		S
Dvnamic	Characteristics					
Ciss	Input Capacitance	V _{DS} = -15 V, V _{GS} = 0 V		2010		pF
Coss	Output Capacitance	f = 1.0 MHz		590		pF
C _{rss}	Reverse Transfer Capacitance			260		pF
Switchin	g Characteristics (Note 2)					•
t _{d(on)}	Turn-On Delay Time	V _{DD} = -15 V, I _D = -1 A		12	22	ns
t _r	Turn-On Rise Time	$V_{GS} = -10 \text{ V}, R_{GEN} = 6 \Omega$		15	27	ns
t _{d(off)}	Turn-Off Delay Time			100	140	ns
t _f	Turn-Off Fall Time			55	80	ns
Qg	Total Gate Charge	V _{DS} = -15 V, I _D = -9 A		21	30	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = -5 V$,		6		nC
Q_{gd}	Gate-Drain Charge			8		nC
Drain-So	urce Diode Characteristics and	Maximum Ratings				
Is	Maximum Continuous Drain-Source Did				-2.1	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = -2.1 A (Note 2)		0.75	-1.2	V
t _{rr}	Source-Drain Reverse Recovery Time	$I_F = -10 \text{ A}, dI_F/dt = 100 \text{ A/}\mu\text{S}$		36	80	ns

^{1:} $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.







Scale 1 : 1 on letter size paper

2: Pulse Test: Pulse Width $\leq 300~\mu\text{s},~\text{Duty Cycle} \leq 2.0\%$

Typical Characteristics

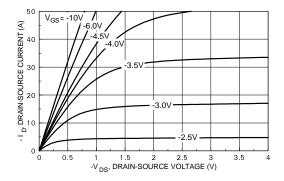
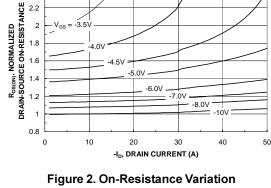


Figure 1. On-Region Characteristics



2.4

with Drain Current and Gate Voltage

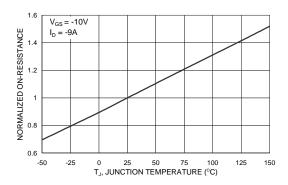


Figure 3. On-Resistance Variation with Temperature

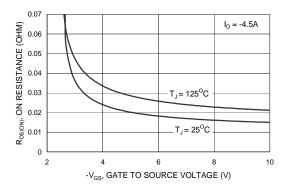


Figure 4. On-Resistance Variation with Gate-to-Source Voltage

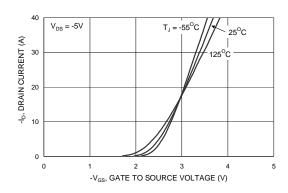


Figure 5. Transfer Characteristics

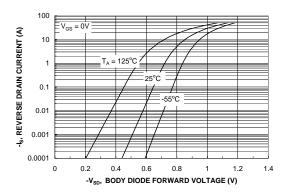
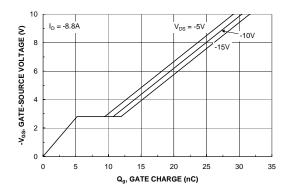


Figure 6. Body Diode Forward Voltage **Variation with Source Current** and Temperature

Typical Characteristics (continued)



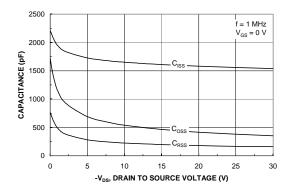
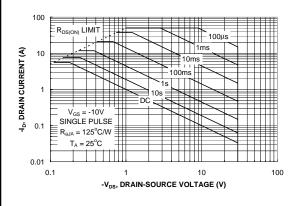


Figure 7. Gate-Charge Characteristics





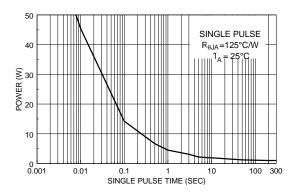


Figure 9. Maximum Safe Operating Area

Figure 10. Single Pulse Maximum Power Dissipation

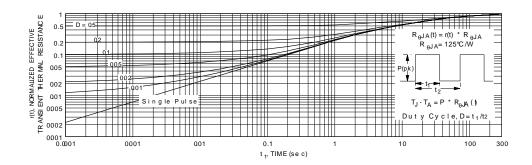


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient themal response will change depending on the circuit board design.

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